

Docket: P910232

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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APR 25 2006

Applicant: Tseng et al.
Serial No.: 10/609,038
Filed: June 27, 2003
For: POWER-ON RESET CIRCUIT WITH
SUPPLY VOLTAGE AND
TEMPERATURE IMMUNITY,
ULTRA-LOW DC LEAKAGE
CURRENT, AND FAST POWER
CRASH REACTION

Examiner: Englund, Terry L.

Group Art Unit: 2816

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

CERTIFICATE OF FACSIMILE TRANSMISSION
I hereby certify that this paper is being facsimile transmitted to:
Commissioner for Patents at fax number 571-273-8300 on April 25,
2006.


Kenton R. Mullins, Reg. No. 36,331


TRANSMITTAL

Sir:

Submitted herewith are:

- (1) Amendment (14 pages including this Transmittal); and
- (2) Deposit Account Authorization: The Commissioner is hereby authorized to charge any needed fees to deposit account 50-1600.

Respectfully submitted,


Kenton R. Mullins
Attorney for Applicants
Registration No. 36,331

April 25, 2006

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Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450**AMENDMENT**

Dear Sir:

This is in response to the January 25, 2006 Office Action issued by the United States Patent and Trademark Office regarding the above-identified application. A response to the Office Action is due three months from the mailing date thereof. Accordingly, this Amendment is being timely filed. Please amend the subject application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 12 of this paper.